Inventor: Hui-Chuan Hung

Serial No.: 10/656,754 Filed: 09/06/2003 For: In-Situ Electron Beam Induced Current Detection

Atturney Doc. No.: 67,200-1152

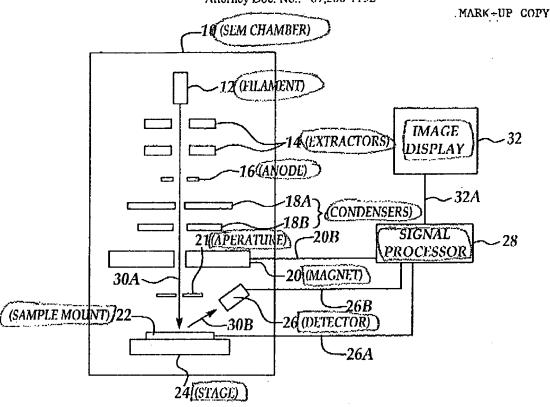
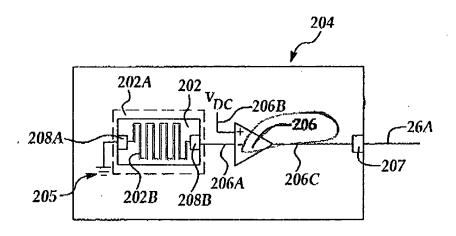


Figure 1



<u>Figure 2A</u>

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Serial No.: 10/656,754 Filed: 09/06/2003

For: In-Situ Electron Beam Induced Current Detection

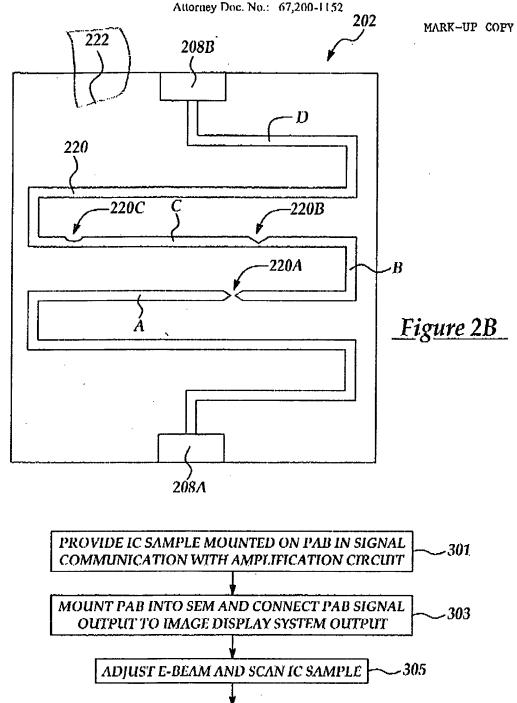


Figure 3

PASS EBIC TO AMPLIFICATION ELECTRONICS AND TO IMAGE DISPLAY SYSTEM TO PRODUCE CURRENT AND/OR

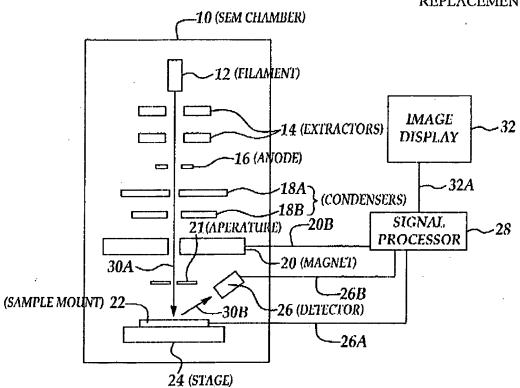
RESISTANCE CONTRAST IMAGE

Inventor: Hui-Chuan Hung

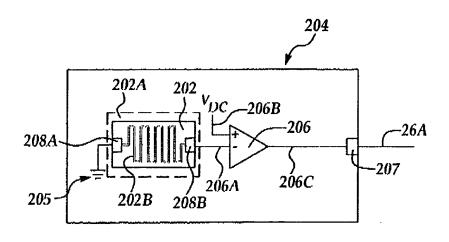
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REPLACEMENT SHEET



<u>Figure 1</u>



<u>Figure 2A</u>

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Attorney Doc. No.: 67,200-1152 202 REPLACEMENT SHEET 222 208B 220 220C 220B 220AFigure 2B 208A PROVIDE IC SAMPLE MOUNTED ON PAB IN SIGNAL 301 COMMUNICATION WITH AMPLIFICATION CIRCUIT MOUNT PAB INTO SEM AND CONNECT PAB SIGNAL -303 **OUTPUT TO IMAGE DISPLAY SYSTEM OUTPUT**

PROVIDE IC SAMPLE MOUNTED ON PAB IN SIGNAL COMMUNICATION WITH AMPLIFICATION CIRCUIT

MOUNT PAB INTO SEM AND CONNECT PAB SIGNAL OUTPUT TO IMAGE DISPLAY SYSTEM OUTPUT

ADJUST E-BEAM AND SCAN IC SAMPLE 305

PASS EBIC TO AMPLIFICATION ELECTRONICS AND TO IMAGE DISPLAY SYSTEM TO PRODUCE CURRENT AND/OR RESISTANCE CONTRAST IMAGE

Figure 3